CD54HC4094, CD74HC4094, CD74HCT4094

Data sheet acquired from Harris Semiconductor
SCHS211E

High−Speed CMOS Logic 8−Stage Shift and Store Bus Register, Three−State

November 1997 − Revised December 2010

Features

- Buffered Inputs
- Separate Serial Outputs Synchronous to Both Positive and Negative Clock Edges For Cascading
- Fanout (Over Temperature Range)
  - Standard Outputs . . . . . 10 LSTTL Loads
  - Bus Driver Outputs . . . . . 15 LSTTL Loads
- Wide Operating Temperature Range . . . −55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
  - 2V to 6V Operation
  - High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V
- HCT Types
  - 4.5V to 5.5V Operation
  - Direct LSTTL Input Logic Compatibility, V_{IL} = 0.8V (Max), V_{IH} = 2V (Min)
  - CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL}, V_{OH}

Description

The ÕHC4094and CD74HCT4094 are 8−stage serial shift registers having a storage latch associated with each stage for strobing data from the serial input to parallel buffered three−state outputs. The parallel outputs may be connected directly to common bus lines. Data is shifted on positive clock transitions. The data in each shift register stage is transferred to the storage register when the Strobe input is high. Data in the storage register appears at the outputs whenever the Output−Enable signal is high.

Two serial outputs are available for cascading a number of these devices. Data is available at the QS_1 serial output terminal on positive clock edges to allow for high−speed operation in cascaded system in which the clock rise time is fast. The same serial information, available at the QS_2 terminal on the next negative clock edge, provides a means for cascading these devices when the clock rise time is slow.

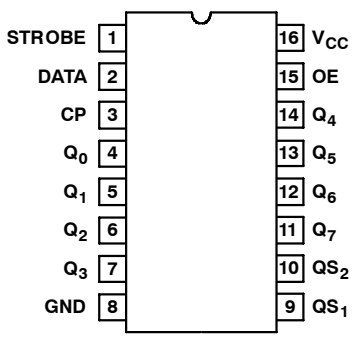
Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC4094F3A	−55 to 125	16 Ld CERDIP
CD74HC4094E	−55 to 125	16 Ld PDIP
CD74HC4094M	−55 to 125	16 Ld SOIC
CD74HC4094MT	−55 to 125	16 Ld SOIC
CD74HC4094M96G3	−55 to 125	16 Ld SOIC
CD74HC4094NSR	−55 to 125	16 Ld SOP
CD74HC4094PW	−55 to 125	16 Ld TSSOP
CD74HC4094PWR	−55 to 125	16 Ld TSSOP
CD74HC4094PWT	−55 to 125	16 Ld TSSOP
CD74HCT4094E	−55 to 125	16 Ld PDIP
CD74HCT4094M	−55 to 125	16 Ld SOIC
CD74HCT4094MT	−55 to 125	16 Ld SOIC
CD74HCT4094M96	−55 to 125	16 Ld SOIC

NOTE: When ordering, use the entire part number. The suffixes 96 and R denote tape and reel. The suffix T denotes a small−quantity reel of 250.

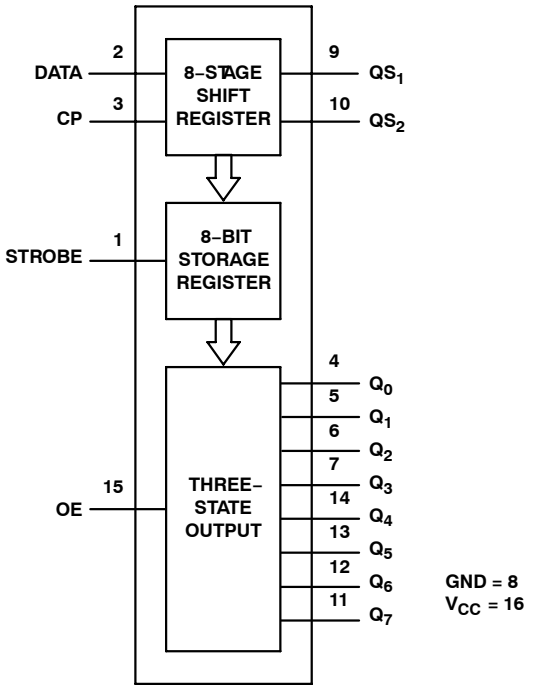
Pinout

CD54HC4094 (CERDIP)
CD74HC4094 (PDIP, SOIC, SOP, TSSOP)
CD74HCT4094 (PDIP, SOIC)
TOP VIEW



CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

Functional Diagram



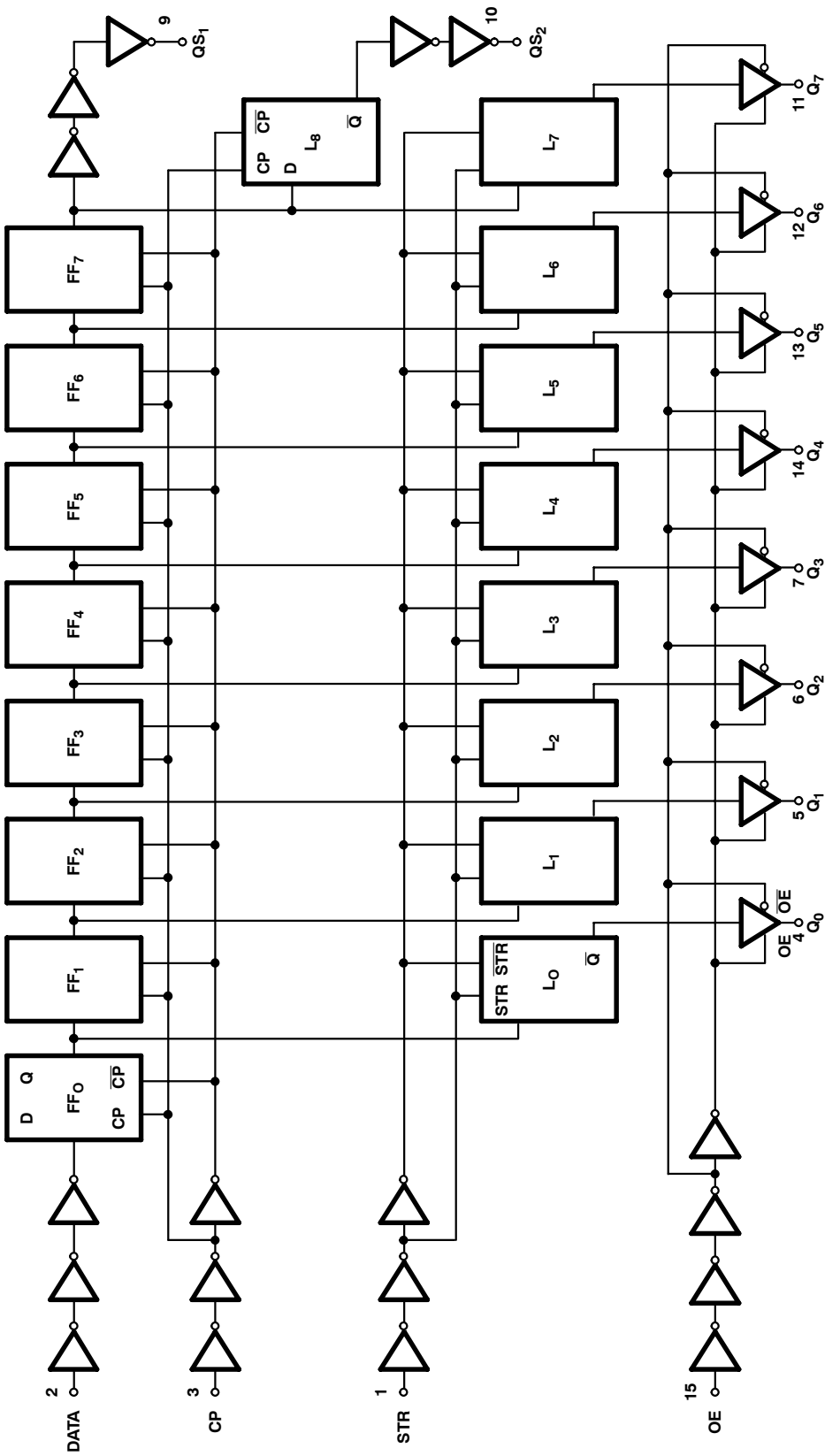
TRUTH TABLE

INPUTS				PARALLEL OUTPUTS		SERIAL OUTPUTS	
CP	**OE**	**STR**	**D**	**Q_0**	**Q_n**	**QS_1** (NOTE 1)	**QS_2**
↑	L	X	X	Z	Z	QÕ6	NC
↓	L	X	X	Z	Z	NC	Q_7
↑	H	L	X	NC	NC	QÕ6	NC
↑	H	H	L	L	Q_n –1	QÕ6	NC
↑	H	H	H	H	Q_n –1	QÕ6	NC
↓	H	H	H	NC	NC	NC	Q_7

H = High Voltage Level, L = Low Voltage Level, X = DonÕt Care, NC = No charge, Z = High Impedance Off–state,
↑ = Transition from Low to High Level, ↓ = Transition from High to Low.
NOTE:

1. At the positive clock edge the information in the seventh register stage is transferred to the 8th register stage and QS1 output.

Logic Diagram



Absolute Maximum Ratings

DC Supply Voltage, V_{CC} . . . . . −0.5V to 7V
DC Input Diode Current, I_{IK}
For V_I < −0.5V or V_I > V_{CC} + 0.5V . . . . . ±20mA
DC Output Diode Current, I_{OK}
For V_O < −0.5V or V_O > V_{CC} + 0.5V . . . . . ±20mA
DC Output Source or Sink Current per Output Pin, I_O
For V_O > −0.5V or V_O < V_{CC} + 0.5V . . . . . ±25mA
DC V_{CC} or Ground Current, I_{CC} . . . . . ±50mA

Operating Conditions

Temperature Range (T_A) . . . . . −55°C to 125°C
Supply Voltage Range, V_{CC}
HC Types . . . . . 2V to 6V
HCT Types . . . . . 4.5V to 5.5V
DC Input or Output Voltage, V_I, V_O . . . . . 0V to V_{CC}
Input Rise and Fall Time
2V . . . . . 1000ns (Max)
4.5V. . . . . 500ns (Max)
6V . . . . . 400ns (Max)

Thermal Information

Package Thermal Impedance, θ_{JA} (see Note 2):
E (PDIP) Package . . . . . 67°C/W
M (SOIC) Package . . . . . 73°C/W
NS (SOP) Package 64oC/W
PW (TSSOP) Package. . . . . 108°C/W
Maximum Junction Temperature (Plastic Package) . . . . . 150°
Maximum Storage Temperature Range . . . . . −65°C to 150°
Maximum Lead Temperature (Soldering 10s) . . . . . 300°
SOIC − Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

2. The package thermal impedance is calculated in accordance with JESD 51−7.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS V_I (V)	TEST CONDITIONS I_O (mA)	V_{CC} (V)	25°C MIN	25°C TYP	25°C MAX	−40°C TO 85°C MIN	−40°C TO 85°C MAX	−55°C TO 125°C MIN	−55°C TO 125°C MAX	UNITS
HC TYPES												
High Level Input Voltage	V_{IH}	−	−	2	1.5	−	−	1.5	−	1.5	−	V
				4.5	3.15	−	−	3.15	−	3.15	−	V
				6	4.2	−	−	4.2	−	4.2	−	V
Low Level Input Voltage	V_{IL}	−	−	2	−	−	0.5	−	0.5	−	0.5	V
				4.5	−	−	1.35	−	1.35	−	1.35	V
				6	−	−	1.8	−	1.8	−	1.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	−0.02	2	1.9	−	−	1.9	−	1.9	−	V
			−0.02	4.5	4.4	−	−	4.4	−	4.4	−	V
			−0.02	6	5.9	−	−	5.9	−	5.9	−	V
High Level Output Voltage TTL Loads			−	−	−	−	−	−	−	−	−	V
			−4	4.5	3.98	−	−	3.84	−	3.7	−	V
			−5.2	6	5.48	−	−	5.34	−	5.2	−	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	−	−	0.1	−	0.1	−	0.1	V
			0.02	4.5	−	−	0.1	−	0.1	−	0.1	V
			0.02	6	−	−	0.1	−	0.1	−	0.1	V
Low Level Output Voltage TTL Loads			−	−	−	−	−	−	−	−	−	V
			4	4.5	−	−	0.26	−	0.33	−	0.4	V
			5.2	6	−	−	0.26	−	0.33	−	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	−	6	−	−	±0.1	−	±1	−	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	−	−	8	−	80	−	160	µA

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS V_I (V)	TEST CONDITIONS I_O (mA)	V_{CC} (V)	25°C MIN	25°C TYP	25°C MAX	−40°C TO 85°C MIN	−40°C TO 85°C MAX	−55°C TO 125°C MIN	−55°C TO 125°C MAX	UNITS
HCT TYPES												
High Level Input Voltage	V_{IH}	–	–	4.5 to 5.5	2	–	–	2	–	2	–	V
Low Level Input Voltage	V_{IL}	–	–	4.5 to 5.5	–	–	0.8	–	0.8	–	0.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	−0.02	4.5	4.4	–	–	4.4	–	4.4	–	V
High Level Output Voltage TTL Loads			−4	4.5	3.98	–	–	3.84	–	3.7	–	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	4.5	–	–	0.1	–	0.1	–	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	–	–	0.26	–	0.33	–	0.4	V
Input Leakage Current	I_I	V_{CC} and GND	0	5.5	–	–	±0.1	–	±1	–	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	5.5	–	–	8	–	80	–	160	µA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI_{CC} (Note 3)	V_{CC} −2.1	–	4.5 to 5.5	–	100	360	–	450	–	490	µA

NOTE:

3. For dual−supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
D	0.4
CP, OE	1.5
STR	1.0

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Table, e.g., 360µA max at 25°C.

Prerequisite for Switching Specifications

CHARACTERISTIC	SYMBOL	V_{CC} (V)	25°C MIN	25°C MAX	−40°C TO 85°C MIN	−40°C TO 85°C MAX	−55°C TO 125°C MIN	−55°C TO 125°C MAX	UNITS
HC TYPES									
CP Pulse Width	t_W	2	80	–	100	–	120	–	ns
		4.5	16	–	20	–	24	–	ns
		6	14	–	17	–	20	–	ns
STR Pulse Width	t_{WH}	2	80	–	100	–	120	–	ns
		4.5	16	–	20	–	24	–	ns
		6	14	–	17	–	20	–	ns

Prerequisite for Switching Specifications **(Continued)**

CHARACTERISTIC	SYMBOL	V_{CC} (V)	25°C		−40°C TO 85°C		−55°C TO 125°C		UNITS
			MIN	MAX	MIN	MAX	MIN	MAX	
Data Set−up Time	t_{SU}	2	50	–	65	–	75	–	ns
		4.5	10	–	13	–	15	–	ns
		6	9	–	11	–	13	–	ns
Data Hold Time	t_H	2	3	–	3	–	3	–	ns
		4.5	3	–	3	–	3	–	ns
		6	3	–	3	–	3	–	ns
STR Set−up Time	t_{SU}	2	100	–	125	–	150	–	ns
		4.5	20	–	25	–	30	–	ns
		6	17	–	21	–	26	–	ns
STR Hold Time	t_H	2	0	–	0	–	0	–	ns
		4.5	0	–	0	–	0	–	ns
		6	0	–	0	–	0	–	ns
Maximum CP Frequency	$f_{CL\ (MAX)}$	2	6	–	5	–	4	–	MHz
		4.5	30	–	24	–	20	–	MHz
		6	35	–	28	–	24	–	MHz
HCT TYPES									
CP Pulse Width	t_W	4.5	16	–	20	–	24	–	ns
STR Pulse Width	t_{WH}	4.5	16	–	20	–	24	–	ns
Data Set−up Time	t_{SU}	4.5	10	–	13	–	15	–	ns
Data Hold Time	t_H	4.5	4	–	4	–	4	–	ns
STR Set−up Time	t_{SU}	4.5	20	–	25	–	30	–	ns
STR Hold Time	t_H	4.5	0	–	0	–	0	–	ns
Maximum CP Frequency	$f_{CL\ (MAX)}$	4.5	30	–	24	–	20	–	MHz

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			−40°C TO 85°C		−55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Propagation Delay Time (Figure 1)	t_{PLH}, t_{PHL}	C_L = 50pF	2	–	–	150	–	190	–	225	ns
CP to QS_1			4.5	–	–	30	–	38	–	45	ns
		C_L =15pF	5	–	12	–	–	–	–	–	ns
		C_L = 50pF	6	–	–	26	–	33	–	38	ns
CP to QS_2	t_{PLH}, t_{PHL}	C_L = 50pF	2	–	–	135	–	170	–	205	ns
			4.5	–	–	27	–	34	–	41	ns
		C_L =15pF	5	–	11	–	–	–	–	–	ns
		C_L = 50pF	6	–	–	23	–	29	–	35	ns
CP to Q_n	t_{PLH}, t_{PHL}	C_L = 50pF	2	–	–	195	–	245	–	295	ns
			4.5	–	–	39	–	49	–	59	ns
			5	–	16	–	–	–	–	–	ns
			6	–	–	33	–	42	–	50	ns
STR to Q_n	t_{PLH}, t_{PHL}	C_L = 50pF	2	–	–	180	–	225	–	270	ns
			4.5	–	–	36	–	45	–	54	ns
			6	–	–	31	–	38	–	46	ns

Switching Specifications Input t_r, t_f = 6ns **(Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			−40°C TO 85°C		−55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Output Enable to Q_n	t_{PZH}, t_{PZL}	C_L = 50pF	2	–	–	175	–	220	–	265	ns
			4.5	–	–	35	–	44	–	53	ns
			6	–	–	30	–	37	–	45	ns
Output Disable to Q_n	t_{PHZ}, t_{PLZ}	C_L = 50pF	2	–	–	125	–	155	–	190	ns
			4.5	–	–	25	–	31	–	38	ns
			6	–	–	21	–	26	–	32	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	2	–	–	75	–	95	–	110	ns
			4.5	–	–	15	–	19	–	22	ns
			6	–	–	13	–	16	–	19	ns
Output Disabling Time	t_{PHZ}, t_{PLZ}	C_L =15pF	5	–	10	–	–	–	–	–	ns
Maximum CP Frequency	f_{MAX}	C_L =15pF	5	–	60	–	–	–	–	–	MHz
Input Capacitance	C_{IN}	C_L = 50pF	–	–	–	10	–	10	–	10	pF
Power Dissipation Capacitance (Notes 4, 5)	C_{PD}	C_L =15pF	5	–	90	–	–	–	–	–	pF
Three−State Output Capacitance	C_O	C_L = 50pF	–	–	–	15	–	15	–	15	pF
HCT TYPES											
Propagation Delay Time (Figure 1)	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	–	–	39	–	–	–	–	ns
CP to QS_1		C_L =15pF	5	–	16	–	–	–	–	–	ns
CP to QS_2	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	–	–	36	–	–	–	–	ns
		C_L =15pF	5	–	15	–	–	–	–	–	ns
CP to Q_n	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	–	–	43	–	–	–	–	ns
		C_L =15pF	5	–	18	–	–	–	–	–	ns
STR to Q_n	t_{PLH}, t_{PHL}	C_L = 50pF	4.5	–	–	39	–	–	–	–	ns
Output Enable to Q_n	t_{PZH}, t_{PZL}	C_L = 50pF	4.5	–	–	35	–	–	–	–	ns
Output Disable to Q_n	t_{PHZ}, t_{PLZ}	C_L = 50pF	4.5	–	–	35	–	–	–	–	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	4.5	–	–	15	–	–	–	–	ns
Output Disabling Time	t_{PHZ}, t_{PLZ}	C_L =15pF	5	–	14	–	–	–	–	–	ns
Maximum CP Frequency	f_{MAX}	C_L =15pF	5	–	60	–	–	–	–	–	MHz
Input Capacitance	C_{IN}	C_L = 50pF	–	–	–	10	–	10	–	10	pF
Power Dissipation Capacitance (Notes 4, 5)	C_{PD}	C_L =15pF	5	–	110	–	–	–	–	–	pF
Three−State Output Capacitance	C_O	C_L = 50pF	–	–	–	15	–	15	–	15	pF

NOTES:

4. C_{PD} is used to determine the dynamic power consumption, per register.
5. $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = Input Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms

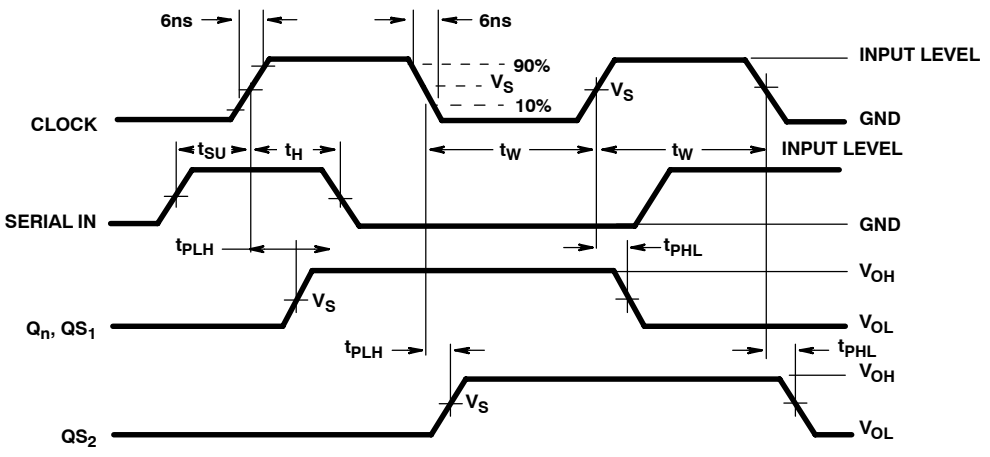


FIGURE 1. DATA PROPAGATION DELAYS, SET–UP AND HOLD TIMES

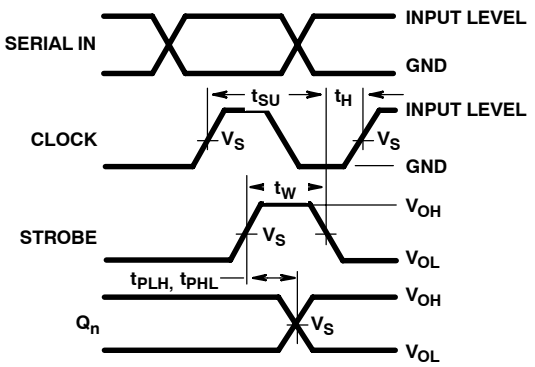


FIGURE 2. STROBE PROPAGATION DELAYS AND SET–UP AND HOLD TIMES

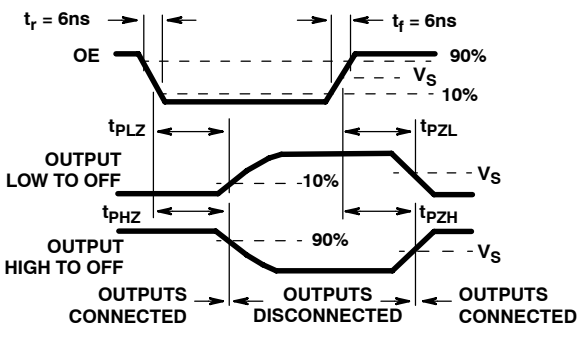


FIGURE 3. ENABLE AND DISABLE TIMES

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD54HC4094F3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54HC4094F3A	Samples
CD74HC4094E	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC4094E	Samples
CD74HC4094M	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094M96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU SN	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094M96G3	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094M96G4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094MG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094MT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094NSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094NSRE4	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4094M	Samples
CD74HC4094PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4094	Samples
CD74HC4094PWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4094	Samples
CD74HC4094PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU | CU SN	Level-1-260C-UNLIM	-55 to 125	HJ4094	Samples
CD74HC4094PWRE4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4094	Samples
CD74HC4094PWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4094	Samples
CD74HC4094PWT	ACTIVE	TSSOP	PW	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4094	Samples
CD74HCT4094E	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT4094E	Samples

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD74HCT4094EE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT4094E	Samples
CD74HCT4094M	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT4094M	Samples
CD74HCT4094M96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU SN	Level-1-260C-UNLIM	-55 to 125	HCT4094M	Samples
CD74HCT4094M96E4	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125		
CD74HCT4094M96G4	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	HCT4094M	
CD74HCT4094ME4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT4094M	Samples
CD74HCT4094MT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT4094M	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

OTHER QUALIFIED VERSIONS OF CD54HC4094, CD74HC4094 :

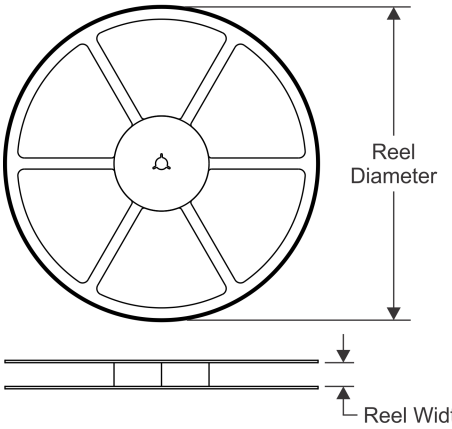
- Catalog: CD74HC4094
- Military: CD54HC4094

NOTE: Qualified Version Definitions:

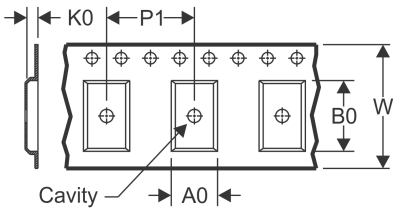
- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION

REEL DIMENSIONS

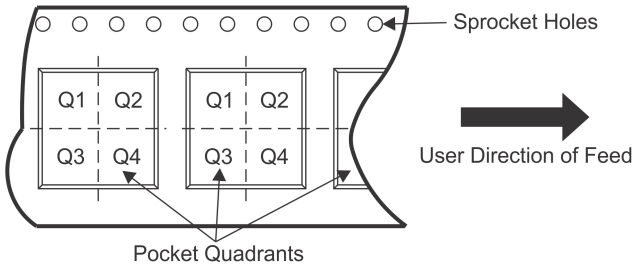


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

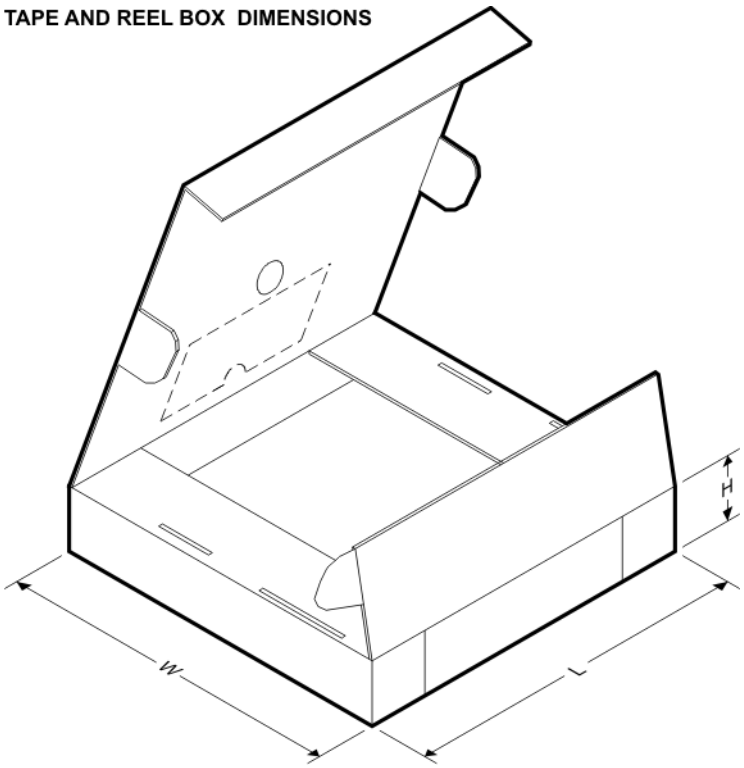
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4094M96	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC4094M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC4094M96G3	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC4094M96G4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC4094NSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD74HC4094PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4094PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4094PWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4094PWT	TSSOP	PW	16	250	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HCT4094M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HCT4094M96	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



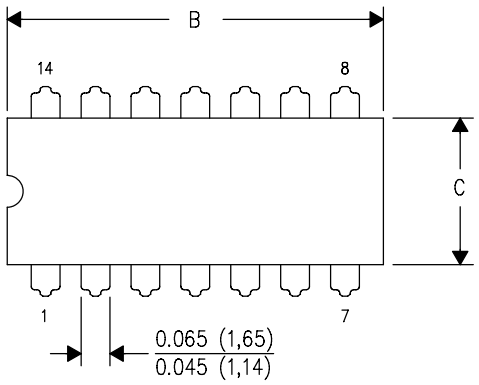
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC4094M96	SOIC	D	16	2500	364.0	364.0	27.0
CD74HC4094M96	SOIC	D	16	2500	333.2	345.9	28.6
CD74HC4094M96G3	SOIC	D	16	2500	364.0	364.0	27.0
CD74HC4094M96G4	SOIC	D	16	2500	333.2	345.9	28.6
CD74HC4094NSR	SO	NS	16	2000	367.0	367.0	38.0
CD74HC4094PWR	TSSOP	PW	16	2000	364.0	364.0	27.0
CD74HC4094PWR	TSSOP	PW	16	2000	367.0	367.0	35.0
CD74HC4094PWRG4	TSSOP	PW	16	2000	367.0	367.0	35.0
CD74HC4094PWT	TSSOP	PW	16	250	367.0	367.0	35.0
CD74HCT4094M96	SOIC	D	16	2500	333.2	345.9	28.6
CD74HCT4094M96	SOIC	D	16	2500	364.0	364.0	27.0

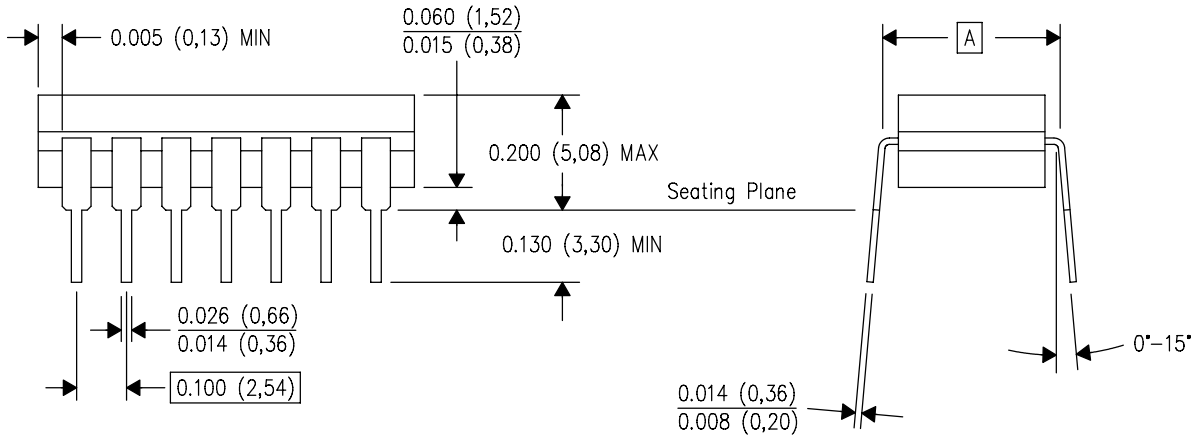
J (R–GDIP–T**)

14 LEADS SHOWN

CERAMIC DUAL IN–LINE PACKAGE



DIM \ PINS **	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



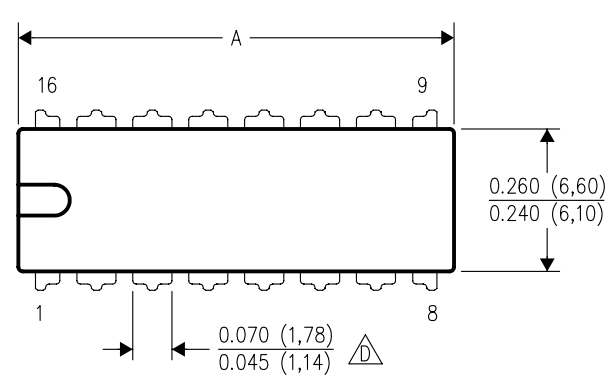
4040083/F 03/03

NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. This package is hermetically sealed with a ceramic lid using glass frit.
D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
E. Falls within MIL STD 1835 GDIP1–T14, GDIP1–T16, GDIP1–T18 and GDIP1–T20.

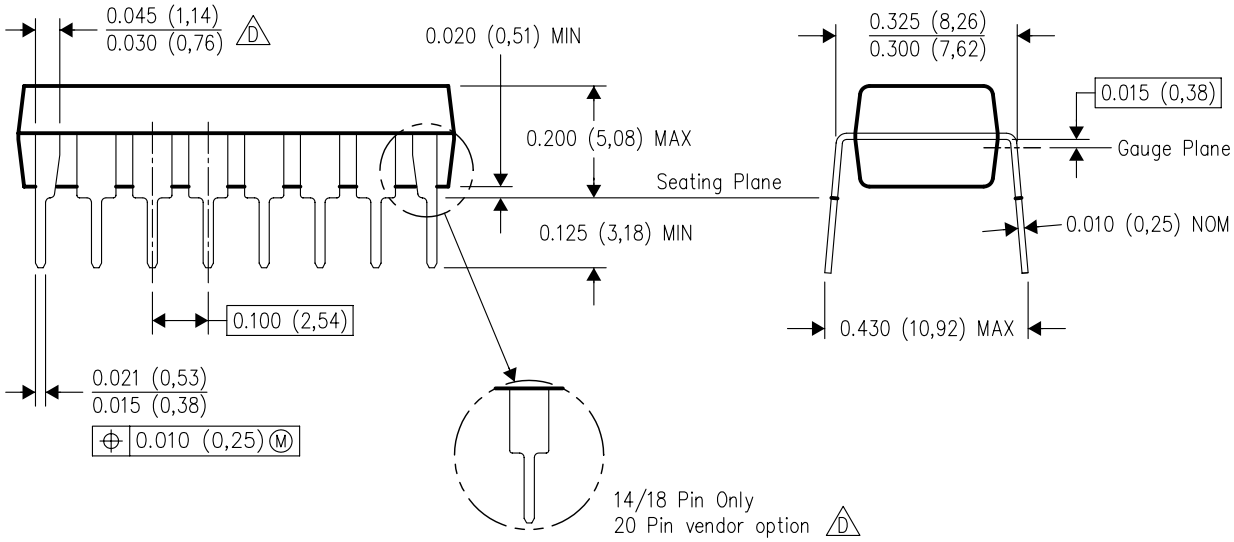
N (R–PDIP–T**)

PLASTIC DUAL–IN–LINE PACKAGE

16 PINS SHOWN



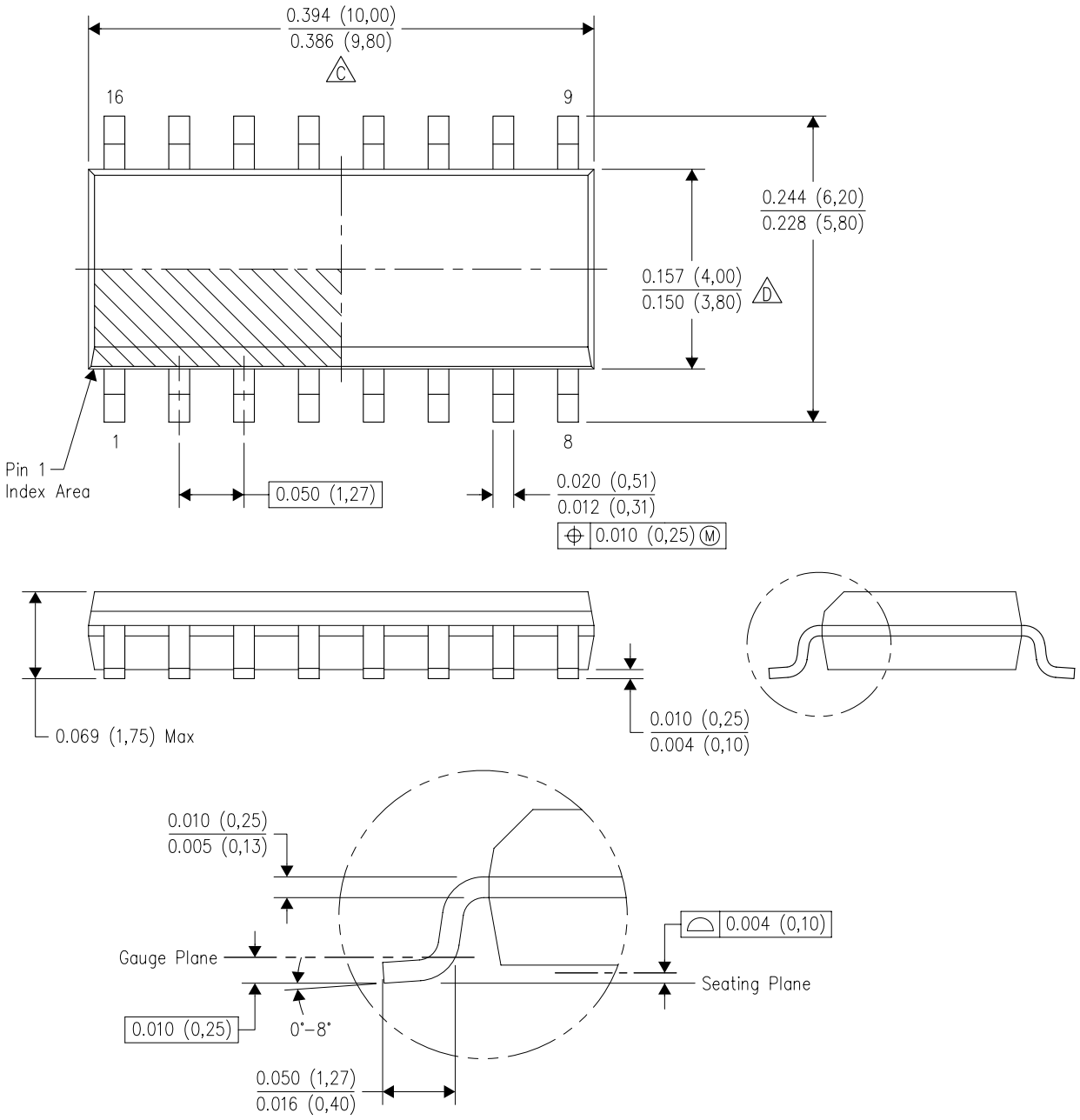
DIM \ PINS **	14	16	18	20
A MAX	0.775 (19,69)	0.775 (19,69)	0.920 (23,37)	1.060 (26,92)
A MIN	0.745 (18,92)	0.745 (18,92)	0.850 (21,59)	0.940 (23,88)
MS–001 VARIATION (C)	AA	BB	AC	AD



4040049/E 12/2002

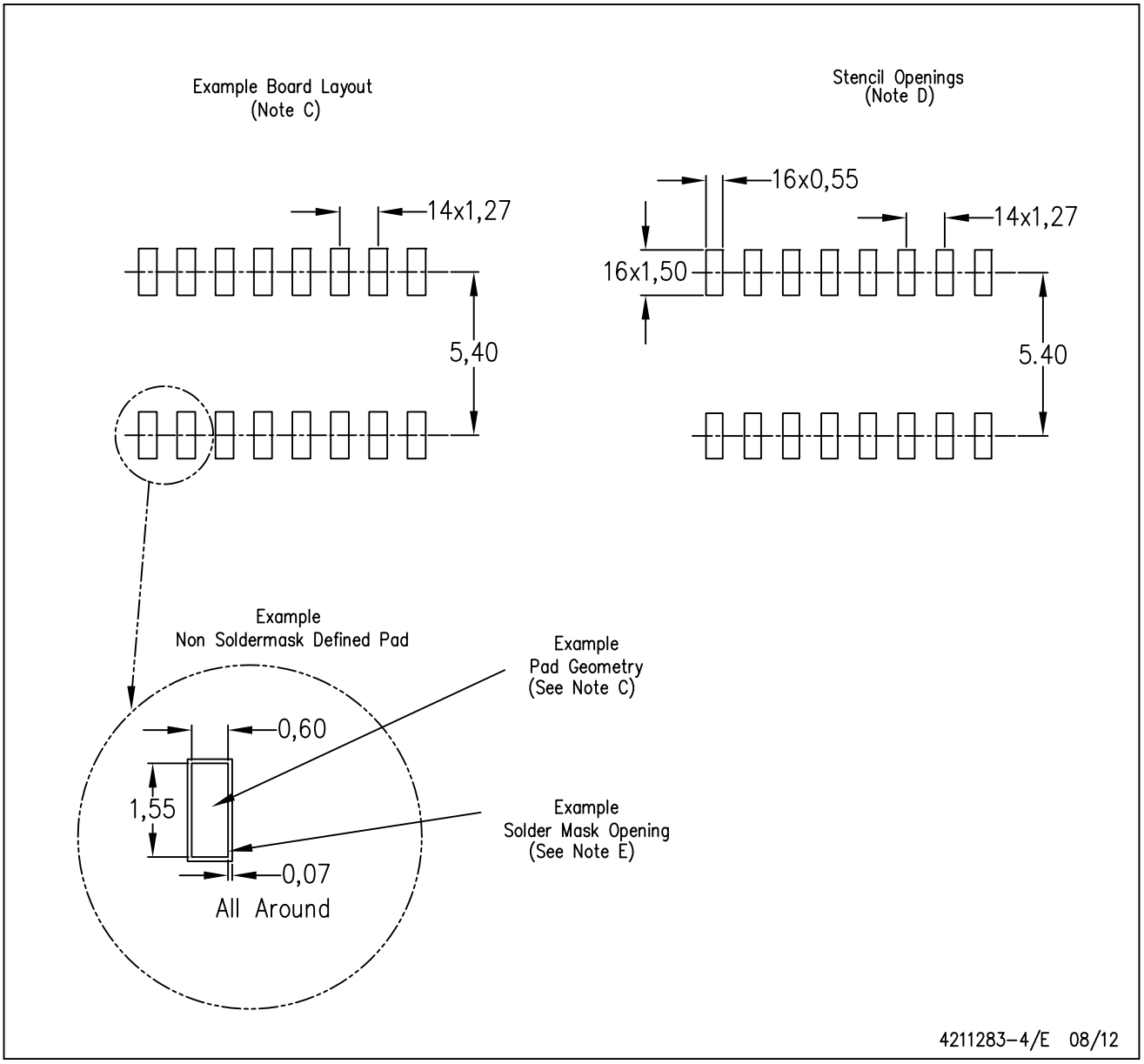
NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Falls within JEDEC MS–001, except 18 and 20 pin minimum body length (Dim A).
D. The 20 pin end lead shoulder width is a vendor option, either half or full width.

D (R–PDSO–G16) PLASTIC SMALL OUTLINE



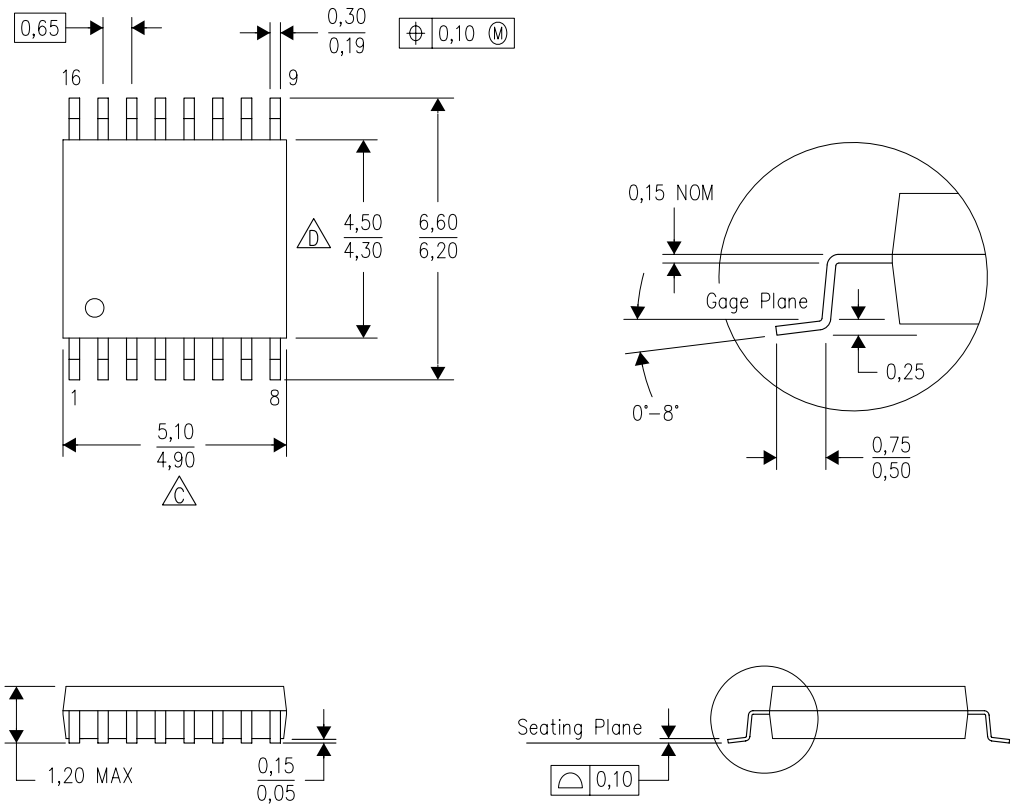
NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
E. Reference JEDEC MS–012 variation AC.

D (R–PDSO–G16) PLASTIC SMALL OUTLINE



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate designs.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC–7525 for other stencil recommendations.
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

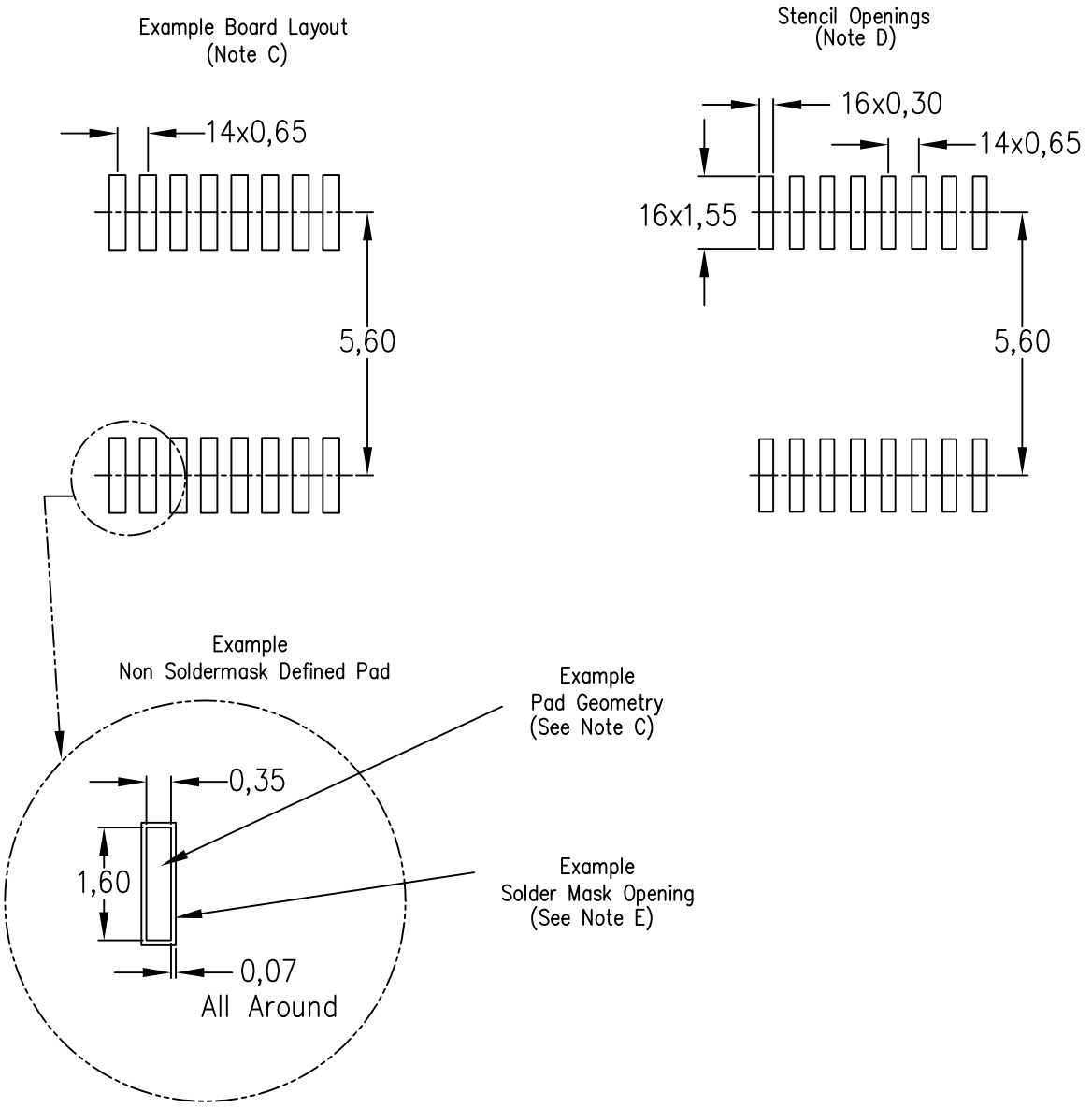
PW (R–PDSO–G16) PLASTIC SMALL OUTLINE



4040064–4/G 02/11

NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
E. Falls within JEDEC MO–153

PW (R–PDSO–G16) PLASTIC SMALL OUTLINE

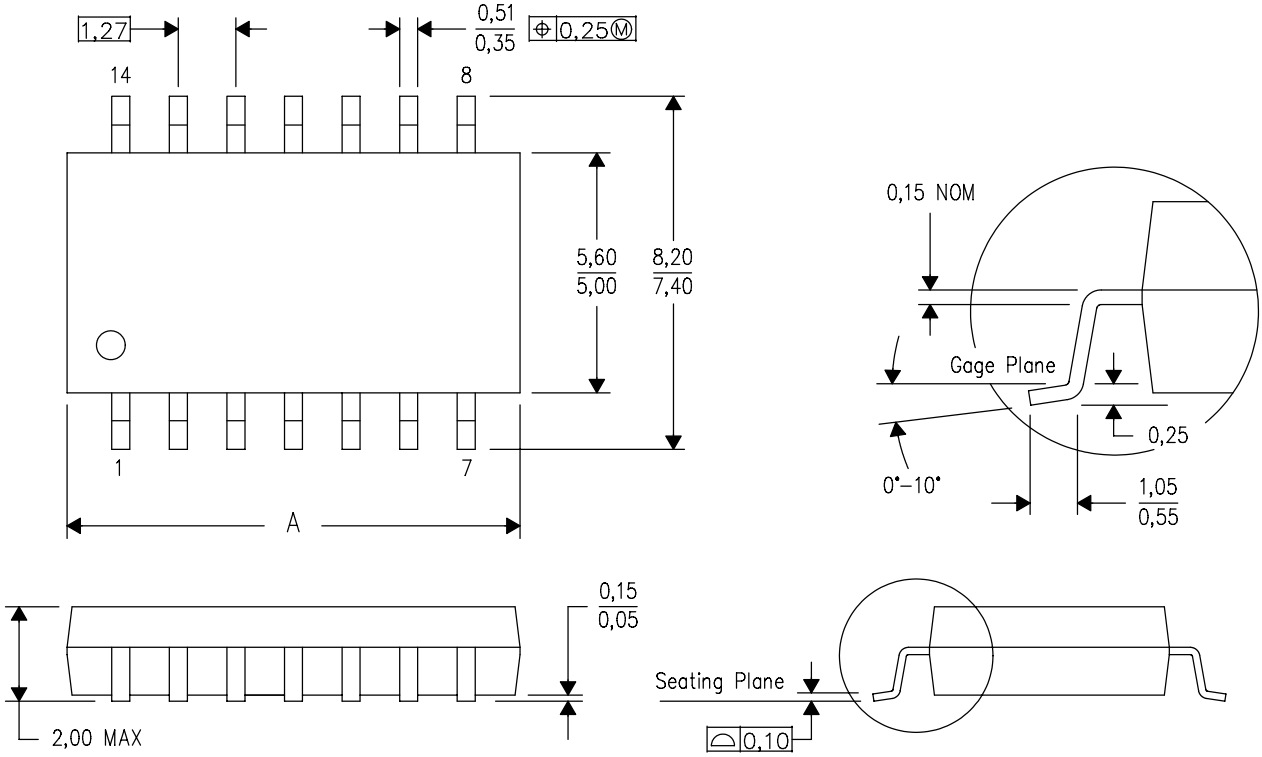


NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate designs.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC–7525 for other stencil recommendations.
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

MECHANICAL DATA

NS (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

14-PINS SHOWN



DIM \ PINS **	14	16	20	24
A MAX	10,50	10,50	12,90	15,30
A MIN	9,90	9,90	12,30	14,70

4040062/C 03/03

NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.

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